

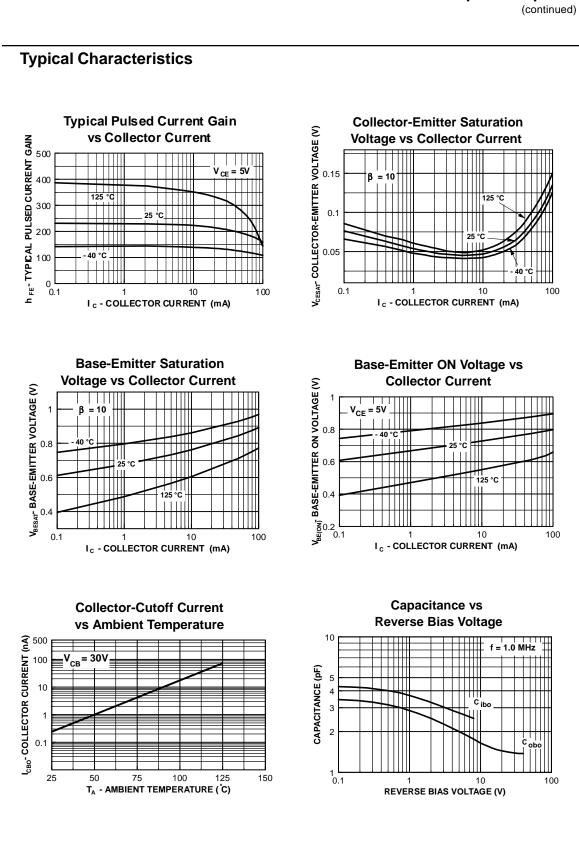
e199 Fairchild Semiconductor Corporation

OFF CHA V(BR)CEO		Test Conditions	Min	Max	Units
	RACTERISTICS Collector-Emitter Breakdown	I <sub>C</sub> = 10 μA, I <sub>B</sub> = 0	60		V
(BR)CEO	Voltage		00		
(BR)CBO	Collector-Base Breakdown Voltage	$I_{\rm C} = 1.0 \text{ mA}, I_{\rm E} = 0$	40		V
(BR)EBO	Emitter-Base Breakdown Voltage	$I_E = 10 \ \mu A, \ I_C = 0$	6.0		V
СВО	Collector-Cutoff Current	$V_{CB} = 30 \text{ V},  T_{A} = 150^{\circ}\text{C}$		5.0	μΑ
CEX	Collector-Cutoff Current	$V_{CE} = 30 \text{ V}, \text{ V}_{EB} = 3.0 \text{ V}$		50	nA
BEX	Reverse Base Current	$V_{CE} = 30 \text{ V}, \text{ V}_{EB} = 3.0 \text{ V}$		50	nA
	RACTERISTICS				
	DC Current Gain	I <sub>C</sub> = 0.1 mA, V <sub>CE</sub> = 1.0 V	40		
FE		$I_{c} = 1.0 \text{ mA}, V_{cE} = 1.0 \text{ V}$	70		
		$I_{\rm C} = 10$ mA, $V_{\rm CE} = 1.0$ V	100	300	
		$I_{C} = 50 \text{ mA}, V_{CE} = 1.0 \text{ V}$ $I_{C} = 100 \text{ mA}, V_{CE} = 1.0 \text{ V}$	60 30		
CE(sat)	Collector-Emitter Saturation Voltage*	$I_{\rm C} = 10 \text{ mA}, V_{\rm CE} = 1.0 \text{ mA}$	30	0.2	V
CE(Sal)	g-	$I_{\rm C} = 50 \text{ mA}, I_{\rm B} = 5.0 \text{ mA}$		0.3	V
(BE(sat)	Base-Emitter Saturation Voltage*	$I_{\rm C} = 10$ mA, $I_{\rm B} = 1.0$ mA $I_{\rm C} = 50$ mA, $I_{\rm B} = 5.0$ mA	0.65	0.85 0.95	V V
SMALL S	IGNAL CHARACTERISTICS				
	IGNAL CHARACTERISTICS	$I_{c} = 20 \text{ mA}, V_{CE} = 20 \text{ V},$ f = 100 MHz	300		MHz
Г			300	4.0	MHz pF
cb	Transition Frequency	f = 100 MHz	300	4.0	_
r Ccb Ceb	Transition Frequency Collector-Base Capacitance	$      f = 100 \text{ MHz} \\ V_{CB} = 5.0 \text{ V}, \text{ I}_{E} = 0, \text{ f} = 1.0 \text{ MHz} $	300		pF
T Cob Ceb Nie	Transition Frequency Collector-Base Capacitance Emitter-Base Capacitance	$\label{eq:cb} \begin{array}{l} f = 100 \text{ MHz} \\ \\ V_{CB} = 5.0 \text{ V}, \text{ I}_{\text{E}} = 0, \text{ f} = 1.0 \text{ MHz} \\ \\ \\ V_{EB} = 0.5 \text{ V}, \text{ I}_{\text{C}} = 0, \text{ f} = 1.0 \text{ MHz} \end{array}$		8.0	pF pF
T C <sub>cb</sub> C <sub>eb</sub> Die	Transition Frequency   Collector-Base Capacitance   Emitter-Base Capacitance   Input Impedance	$\label{eq:constraint} \begin{array}{l} f = 100 \text{ MHz} \\ V_{CB} = 5.0 \text{ V}, \text{ I}_{E} = 0, \text{ f} = 1.0 \text{ MHz} \\ V_{EB} = 0.5 \text{ V}, \text{ I}_{C} = 0, \text{ f} = 1.0 \text{ MHz} \\ V_{CE} = 10 \text{ V}, \text{ I}_{C} = 1.0 \text{ mA}, \text{f} = 1.0 \text{ kHz} \end{array}$	1.0	8.0 10	pF
T Ceb Deb Die Die Die	Transition Frequency   Collector-Base Capacitance   Emitter-Base Capacitance   Input Impedance   Small-Signal Current Gain   Output Admittance	$\begin{array}{l} f = 100 \text{ MHz} \\ \hline V_{CB} = 5.0 \text{ V}, \text{ I}_{E} = 0, \text{ f} = 1.0 \text{ MHz} \\ \hline V_{EB} = 0.5 \text{ V}, \text{ I}_{C} = 0, \text{ f} = 1.0 \text{ MHz} \\ \hline V_{CE} = 10 \text{ V}, \text{ I}_{C} = 1.0 \text{ mA}, \text{f} = 1.0 \text{ kHz} \\ \hline V_{CE} = 10 \text{ V}, \text{I}_{C} = 1.0 \text{ mA}, \text{f} = 1.0 \text{ kHz} \end{array}$	1.0 100	8.0 10 400	pF pF kΩ
T Cob Ceb Nie Nie Noe	Transition Frequency Collector-Base Capacitance Emitter-Base Capacitance Input Impedance Small-Signal Current Gain		1.0 100	8.0 10 400	pF pF kΩ
T Ceb Die Die Die Switchi	Transition Frequency Collector-Base Capacitance Emitter-Base Capacitance Input Impedance Small-Signal Current Gain Output Admittance NG CHARACTERISTICS	$      f = 100 \text{ MHz} \\ V_{CB} = 5.0 \text{ V}, I_E = 0, f = 1.0 \text{ MHz} \\ V_{EB} = 0.5 \text{ V}, I_C = 0, f = 1.0 \text{ MHz} \\ V_{CE} = 10 \text{ V}, I_C = 1.0 \text{ mA}, f = 1.0 \text{ kHz} \\ V_{CE} = 10 \text{ V}, I_C = 1.0 \text{ mA}, f = 1.0 \text{ kHz} \\ V_{CE} = 10 \text{ V}, I_C = 1.0 \text{ mA}, f = 1.0 \text{ kHz} \\ \end{array} $	1.0 100	8.0 10 400 40	pF pF kΩ μS
T Ceb Die Die Die Switchi	Transition Frequency Collector-Base Capacitance Emitter-Base Capacitance Input Impedance Small-Signal Current Gain Output Admittance NG CHARACTERISTICS Delay Time		1.0 100	8.0 10 400 40 35	pF pF kΩ μS

NPN (Is=6.734f Xti=3 Eg=1.11 Vaf=74.03 Bf=416.4 Ne=1.259 Ise=6.734 Ikf=66.78m Xtb=1.5 Br=.7371 Nc=2 Isc=0 Ikr=0 Rc=1 Cjc=3.638p Mjc=.3085 Vjc=.75 Fc=.5 Cje=4.493p Mje=.2593 Vje=.75 Tr=239.5n Tf=301.2p Itf=.4 Vtf=4 Xtf=2 Rb=10)

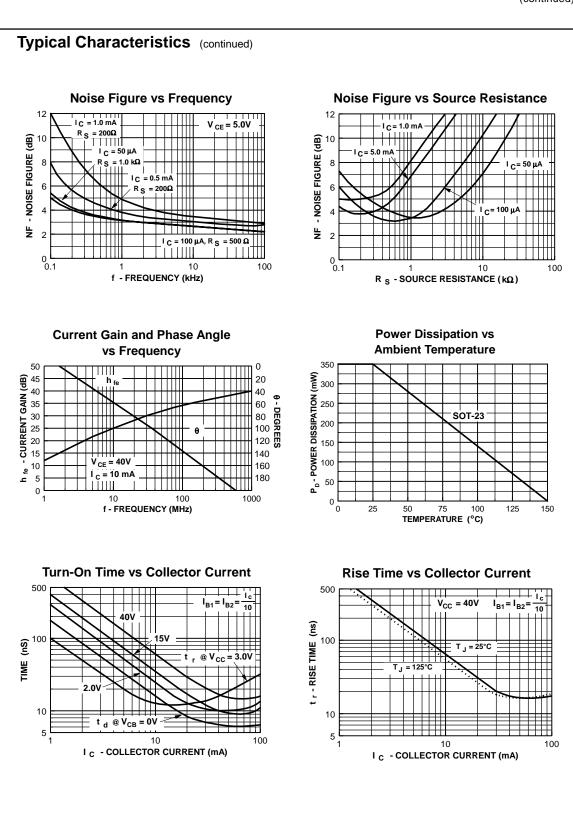
**NPN General Purpose Amplifier** 

ed)



**NPN General Purpose Amplifier** 

(continued)



**NPN General Purpose Amplifier** (continued) Typical Characteristics (continued) Storage Time vs Collector Current Fall Time vs Collector Current 500 500 I<sub>B2</sub>= **B**1 B2 B t s- STORAGE TIME (ns) T j = 25°C Vcc = 40V t <sub>f</sub> - FALL TIME (ns)  $\left\{\cdot\right\}$ 100 T<sub>J</sub> = 125°C 10 10 5 5 10 I c - COLLECTOR CURRENT (mA) 100 10 1 100 1 I C - COLLECTOR CURRENT (mA) **Test Circuits** 3.0 V 0 **\$** 275 Ω ► 300 ns 10.6 V Duty Cycle = 2% 10 KΩ Ŵ < 4.0 pF - 0.5 V < 1.0 ns 🔸 FIGURE 1: Delay and Rise Time Equivalent Test Circuit 3.0 V  $10 < t_1 < 500 \, \mu s$ → t, 10.9 V 275 Ω Duty Cycle = 2% 10 KΩ 0 < 4.0 pF 1N916 - 9.1 V 🗲 < 1.0 ns → FIGURE 2: Storage and Fall Time Equivalent Test Circuit

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